Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,361	CHEN ET AL.	
	Examiner	Art Unit	
	Mathieu D. Vargot	1732	

SEARCHED			
Class	Subclass	Date	Examiner
264	1.1, 2.5, 85, 1.34	3/4/06	MDV

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR